

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination	
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		Examiner	Art Unit	Page 1 of 3
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Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination	
		10/063,934	SATO, TAKAYUKI	
Examiner		Art Unit		Page 2 of 3
Ajay M. Bhatia		2145		

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		Examiner Ajay M. Bhatia	Art Unit 2145	Page 3 of 3

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